


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/708,836	BEENAU ET AL.	
	Examiner	Art Unit	
	Nam V. Nguyen	2635	

SEARCHED			
Class	Subclass	Date	Examiner
340	5.53	5/19/2006	NN
340	5.2	5/19/2006	NN
340	5.4+	5/19/2006	NN
340	5.52	5/19/2006	NN
340	5.6	5/19/2006	NN
340	5.8+	5/19/2006	NN
340	10.1	5/19/2006	NN
340	10.4-10.5	5/19/2006	NN
235	379	5/19/2006	NN
235	380	5/19/2006	NN
235	492	5/19/2006	NN
705	35,54,76	5/19/2006	NN
705	186,194	5/19/2006	NN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East Search: USPAT; US-PUB; EPO;JPO; and Derwent. (updated search).	5/19/2006	NN